Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/718,321	BAILLY ET AL.	
Examiner	Art Unit	
Yunsoo Kim	1644	

	SEAR	CHED	
Class	Subclass	Date	Examiner
530	387.1	1/13/2005	YK
435	326	1/13/2005	YK
424	130.1	1/13/2005	YK

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
SEQ ID NO:1 from stic	1/13/2005	ΥK	
inventor search in PALM and NPL	1/13/2005	YK	
domestic prioirity considered 60/295907 6/3/2001	1/13/2005	YK	